

## Cp E 432: Testing of Computing Systems

### Electrical and Computer Engineering

Physical defects from semiconductor manufacture, fault modeling and simulation, fault activation and detection in digital systems, digital test pattern synthesis, test coverage, test compaction, online/offline/BIST testing concepts, design-for-test, design-for-manufacture, system testability and diagnosability.

3 Credits

### Prerequisites

- [EI E 351: Electronics Circuits I](#) \$target.descriptions.MinimumGrade\$
- [EI E 385: Advanced Digital Systems](#) \$target.descriptions.MinimumGrade\$
- [EI E 386: Advanced Digital Systems Laboratory](#) \$target.descriptions.MinimumGrade\$

### Instruction Type(s)

- Lecture: Lecture for Cp E 432

### Subject Areas

- [Computer Engineering, General](#)

### Related Areas

- [Computer Hardware Engineering](#)

